

測試報告

Test Report

號碼(No.) : CE/2010/23590 日期(Date) : 2010/03/08 頁數(Page) : 1 of 4

億光電子工業股份有限公司

EVERLIGHT ELECTRONICS CO., LTD.

台北縣土城市中央路三段76巷25號

NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.



以下測試樣品係由客戶送樣，且由客戶聲稱並經客戶確認如下 (The following samples was/were submitted and identified by/on behalf of the client as):

BASIC INFORMATION	
Type of Product	PHOTO COUPLER SOP類-含鹵素機種 (EL81x, EL35x, EL3Hx, EL2xx, ELD2xx, EL10xx, EL11xx)
Supplier Company Name	EVERLIGHT
Address	NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIWAN, R. O. C.
Tel/Fax/Email	TEL:886-2-267-2000 EXT:1203
	FAX:886-2-267-9948
	E-MAIL: meelin@everlight.com
Contact Person	LIN HSIAO HUA
EVERLIGHT REPORT NO	EVERLIGHT-EL81x, EL35x, EL3Hx, EL2xx, ELD2xx, EL10xx, EL11xx-SGS-08/03/2010
PRODUCT INFORMATION	
Product/component Sample description	ISOLATION UNIT
Quantity (numbers or weight)	0.082g
Supplier P/N	EL81x, EL35x, EL3Hx, EL2xx, ELD2xx, EL10xx, EL11xx
Product Lot No	3B-HB
Country of Origin	TAIWAN
TEST INFORMATION	
Digital Photo(s) of sample(s) after being prepared	JPG EMBEDDED IN EACH REPORT
Sample preparation	CUTTING
Test Method	Halogen-BS EN 14582
PQL and/or MDL	Halogen: 50 mg/kg
Name of Analyzer	Halogen: Rita Chen

收件日期(Sample Receiving Date) : 2010/02/26

測試期間(Testing Period) : 2010/02/26 TO 2010/03/08

=====
 測試結果(Test Results) : 請見下一頁 (Please refer to next pages).

Shin-Jyh Chen

Shin-jyh Chen / Asst. Manager

Signed for and on behalf of

SGS TAIWAN LTD.

Chemical Laboratory - Taipei

Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company.

除非另有說明，此報告結果僅對測試之樣品負責。本報告未經本公司書面許可，不可部分複製。

This Test Report is issued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at http://www.sgs.com/terms_and_conditions.htm. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law.

測試報告

Test Report

號碼(No.) : CE/2010/23590 日期(Date) : 2010/03/08 頁數(Page) : 2 of 4

億光電子工業股份有限公司

EVERLIGHT ELECTRONICS CO., LTD.

台北縣土城市中央路三段76巷25號

NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.



測試結果(Test Results)

測試部位(PARTNAME)NO.1 : 本體 (BODY)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				NO.1
鹵素 / Halogen				
鹵素 (氟) / Halogen-Fluorine (F) (CAS No.: 014762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素 (氯) / Halogen-Chlorine (Cl) (CAS No.: 022537-15-1)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	128
鹵素 (溴) / Halogen-Bromine (Br) (CAS No.: 010097-32-2)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	5410
鹵素 (碘) / Halogen-Iodine (I) (CAS No.: 014362-44-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.

備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)

Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. 除非另有說明, 此報告結果僅對測試之樣品負責。本報告未經本公司書面許可, 不可部分複製。

This Test Report is issued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at http://www.sgs.com/terms_and_conditions.htm. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law.

測試報告

Test Report

號碼(No.) : CE/2010/23590 日期(Date) : 2010/03/08 頁數(Page) : 3 of 4

億光電子工業股份有限公司

EVERLIGHT ELECTRONICS CO., LTD.

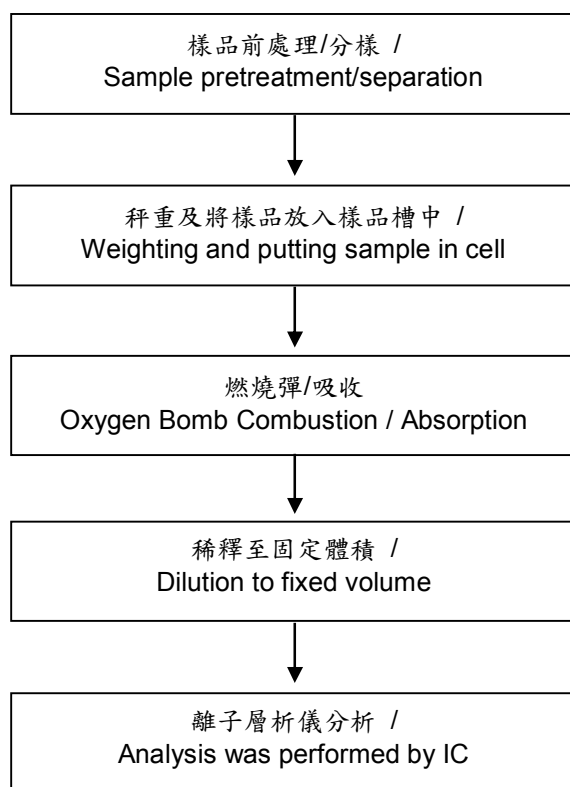
台北縣土城市中央路三段76巷25號

NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.



鹵素分析流程圖 / Analytical flow chart of halogen content

- 1) 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 2) 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. 除非另有說明，此報告結果僅對測試之樣品負責。本報告未經本公司書面許可，不可部分複製。

This Test Report is issued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at http://www.sgs.com/terms_and_conditions.htm. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law.

測試報告

Test Report

號碼(No.) : CE/2010/23590 日期(Date) : 2010/03/08 頁數(Page) : 4 of 4

億光電子工業股份有限公司

EVERLIGHT ELECTRONICS CO., LTD.

台北縣土城市中央路三段76巷25號

NO. 25, LANE 76, SEC. 3, CHUNG YANG ROAD, TUCHENG, TAIPEI, TAIWAN, R. O. C.



** 報告結尾 (End of Report) **

Unless otherwise stated the results shown in this test report refer only to the sample(s) tested. This test report cannot be reproduced, except in full, without prior written permission of the Company. 除非另有說明，此報告結果僅對測試之樣品負責。本報告未經本公司書面許可，不可部分複製。

This Test Report is issued by the Company under its General Conditions of Service printed overleaf or available on request and accessible at http://www.sgs.com/terms_and_conditions.htm. Attention is drawn to the limitation of liability, indemnification and jurisdiction issues defined therein. Any holder of this Test Report is advised that information contained hereon reflects the Company's findings at the time of its intervention only and within the limits of Client's instructions, if any. The Company's sole responsibility is to its Client and this document does not exonerate parties to a transaction from exercising all their rights and obligations under the transaction documents. Any unauthorized alteration, forgery or falsification of the content or appearance of this document is unlawful and offenders may be prosecuted to the fullest extent of the law.